DATE: December 10, 2025

PCN #: 2768

PCN Title: Qualification of Internal "Diodes Technology (Cheng Du) Company Limited" (CAT) along with New Internal Wafer Source (OFAB) and Shanghai Assembly and Test Site (SAT) as Additional Assembly & Test (A/T) Sites with Standardization of Assembly Bill of Materials, and Change of Mold Compound Type as well as Die Attach Material at Currently Qualified A/T Site for Select Automotive Products

Dear Customer:

This is an announcement of change(s) to products that are currently being offered by Diodes Incorporated.

We request that you acknowledge receipt of this notification within 30 days of the date of notification by contacting your local Diodes sales representative. If you require samples for evaluation purposes, please submit a corresponding request within 30 days as well. Otherwise, samples may not be built prior to the implementation of the announced change(s).

The change(s) announced in this PCN will not be implemented prior to the target implementation date, i.e. 90 days from the stated notification date, unless Diodes receives written customer approval before that date.

Previously agreed upon customer specific product and/or process change requirements will be addressed separately.

For questions or clarification regarding this PCN, please contact your local Diodes sales representative.

Sincerely,

Diodes Incorporated PCN Team

PRODUCT CHANGE NOTICE PCN-2768-REV1

Notification Date:	Implementation Date:	Product Family:	Change Type:	PCN #:
December 10, 2025	March 10, 2026	Discrete Semiconductor	Additional Assembly & Test Site / Additional Wafer Source / Assembly Bill of Materials	**2768**

TITLE

Qualification of Internal "Diodes Technology (Cheng Du) Company Limited" (CAT) along with New Internal Wafer Source (OFAB) and Shanghai Assembly and Test Site (SAT) as Additional Assembly & Test (A/T) Sites with Standardization of Assembly Bill of Materials, and Change of Mold Compound Type as well as Die Attach Material at Currently Qualified A/T Site for Select Automotive Products

DESCRIPTION OF CHANGE

This PCN is being issued to notify customers that in order to assure continuity of supply, Diodes has qualified internal "Diodes Technology (Cheng Du) Company Limited" (CAT) located in Chengdu, China as additional Assembly and Test (A/T) site along with new internal wafer source (OFAB) and qualified internal Shanghai Assembly and Test site (SAT) located in Shanghai, China for automotive products listed in Table 1 – 3 below. These A/T site and wafer source changes also include standardization of assembly bill of materials, i.e. die attach material, mold compound, bond wire, lead frame types, date code marking and back metal composition.

In addition, Diodes Incorporated has qualified new die attach and mold compound types at the currently qualified assembly and test site (CAT) for select automotive products listed in tables 4 below.

Full electrical characterization and high reliability testing has been completed on representative part numbers to ensure there is no change to device functionality or electrical specifications in the datasheet.

IMPACT

Continuity of Supply. No change in datasheet electrical parameters and product performance. There will be no change to Fit or Function of products affected for the parts listed in Table 1 - 3. There will be no change to Form, Fit or Function of products affected for the parts listed in Table 4.

PRODUCTS AFFECTED

Please see the attached part list and top marking changes in the following tables:

Table 1 – Affected part list to qualify CAT as additional A/T site with standardization of assembly bill of materials at CAT

Table 2 – Affected part list to qualify OFAB as additional wafer source and CAT as additional A/T site with standardization of bill of materials at OFAB and CAT

Table 3 – Affected part list to qualify SAT as additional A/T site with standardization of assembly bill of materials at SAT

Table 4 – Affected Part List to Epoxy Die Attach Type at Currently Qualified AT Site (CAT)

Table 5 – Part Marking Format

WEB LINKS

Manufacturer's Notice:	https://www.diodes.com/quality/product-change-notices/diodes-product-change-notices/
For More Information Contact:	https://www.diodes.com/about/contact-us/contact-sales/
Data Sheet:	https://www.diodes.com/catalog/

DISCLAIMER

Unless a Diodes Incorporated Sales representative is contacted in writing within 30 days from the notification date of this PCN, all changes described in this announcement are considered approved.

Table 1 - Affected part list to qualify CAT as additional A/T site with standardization of assembly bill of materials at CAT

DMP2045UQ-13**	DMP2123LQ-7**	FZT949QTA*	FZT956QTA*	ZXMN3A14FQTA***	ZXMP10A13FQTA*
DMP2045UQ-7**	DMP3098LQ-7**	FZT953QTA*			

Table 2 - Affected part list to qualify OFAB as additional wafer source and CAT as additional A/T site with standardization of bill of materials at OFAB and CAT

BC846BQ-13-F*	BC847BVNQ-7*	DDTA114ECAQ-13-F*	DDTC114YCAQ-13-F*	DDTC143ZCAQ-13-F*	MMBT2222AQ-7-F*
BC846BQ-7-F*	BC847CQ-7-F*	DDTA114ECAQ-7-F*	DDTC114YCAQ-7-F*	DDTC143ZCAQ-7-F*	MMBT2907AQ-7-F*
BC846BWQ-7-F*	BC847CWQ-7-F*	DDTA144ECAQ-13-F*	DDTC115EUAQ-7-F*	DDTC144ECAQ-13-F*	MMBT3904Q-7-F*
BC847BQ-7-F*	BC848CQ-7-F*	DDTC114ECAQ-13-F*	DDTC123ECAQ-7-F*	DDTC144ECAQ-7-F*	MMBT3906Q-7-F*
BC847BSQ-7-F*	BC857BQ-7-F*	DDTC114ECAQ-7-F*	DDTC124EUAQ-7-F*	DDTC144EUAQ-13-F*	MMBT4401Q-13-F*
BC847BVCQ-7*	BC857BSQ-7-F*	DDTC114EUAQ-7-F*	DDTC143TCAQ-7-F*	DDTC144EUAQ-7-F*	MMDT2907VQ-7*

Table 3 - Affected part list to qualify SAT as additional A/T site with standardization of assembly bill of materials at SAT

BFS17NQTA	FMMT494QTC	FZT560QTC	ZTP25040DFHQTA*	ZXTN2018FQTA*	ZXTP2027FQTA*
FMMT494QTA	FZT560QTA	ZTN23015CFHQTA			

Table 4 – Affected Part List to Change Die Attach Material at Currently Qualified A/T Site (CAT)

BCP5316QTA	BCP5610QTC	BCP5616TQTA	DSS60601MZ4Q-13****	FZT489QTA	ZXTN25100DGQTA
BCP5416QTA	BCP5616QTA	BCP5616TQTC	DZT5551Q-13	FZT491AQTA	ZXTP07060BGQTC
BCP5610QTA	BCP5616QTC	DSS60600MZ4Q-13****	DZTA42Q-13	ZXTN07060BGQTC	

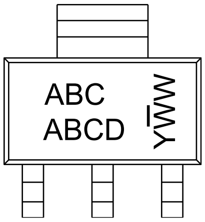
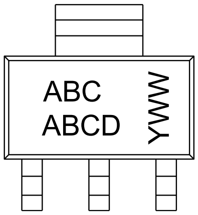
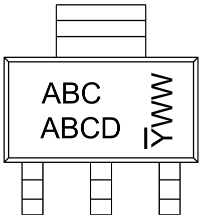
Note: “*” Change bond wire from Au to PdCu

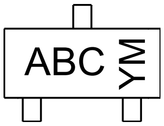
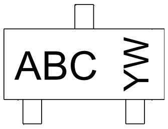
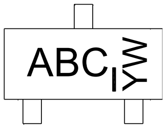
Note: “**” Change bond wire from Cu to PdCu

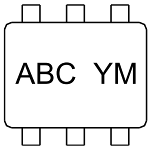
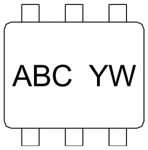
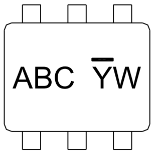
Note: “***” Change bond wire from Au to Cu

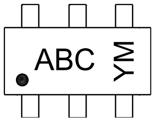
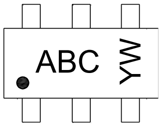
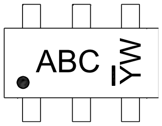
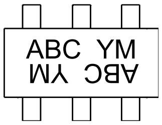
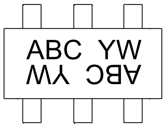
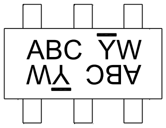
Note: “****” Change mold compound type

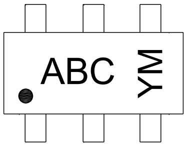
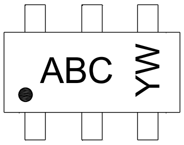
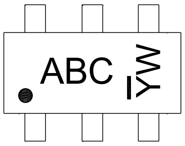
Table 5: Marking Code Format –

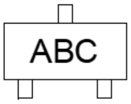
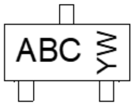
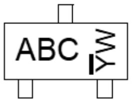
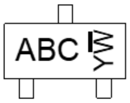
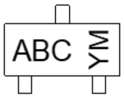
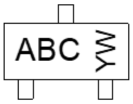
	CURRENT	NEW	
SOT223	**NAT** **(Diodes Internal A/T Site - Neuhaus, Germany)**	**SAT** **(Diodes Internal A/T Site - Shanghai, China)**	**CAT** **(Diodes Internal A/T Site - Chengdu, China)**
	Bar "-" above Week (W) of Date Code for NAT	**No bar on Date Code**	**Bar "-" above Year (Y) of Date Code**
	Marking Format Example: 	Marking Format Example: 	Marking Format Example: 

	CURRENT	NEW	
SOT323	**SAT** **(Diodes Internal A/T Site - Shanghai, China)**	**SAT** **(Diodes Internal A/T Site - Shanghai, China)**	**CAT** **(Diodes Internal A/T Site - Chengdu, China)**
	No Bar "-" on Date Code for SAT	**Date code format change from YM to YW ;** **No bar on Date Code**	**Date code format change from YM to YW ;** **Bar "-" above Y (Year) of Date Code**
	Marking Format Example: 	Marking Format Example: 	Marking Format Example: 

	CURRENT	NEW	
SOT563	**SAT** **(Diodes Internal A/T Site - Shanghai, China)**	**SAT** **(Diodes Internal A/T Site - Shanghai, China)**	**CAT** **(Diodes Internal A/T Site - Chengdu, China)**
	No Bar "-" on Date Code for SAT	**Date code format change from YM to YW ;** **No bar on Date Code**	**Date code format change from YM to YW ;** **Bar "-" above Y (Year) of Date Code**
	Marking Format Example: 	Marking Format Example: 	Marking Format Example: 

	CURRENT	NEW	
SOT363	SAT (Diodes Internal A/T Site - Shanghai, China)	SAT (Diodes Internal A/T Site - Shanghai, China)	CAT (Diodes Internal A/T Site - Chengdu, China)
	No Bar "-" on Date Code for SAT	Date code format change from YM to YW ; No bar on Date Code	Date code format change from YM to YW ; Bar "-" above Y (Year) of Date Code
	Marking Format Example: 	Marking Format Example: 	Marking Format Example: 
			

	CURRENT	NEW	
SOT26	SAT (Diodes Internal A/T Site - Shanghai, China)	SAT (Diodes Internal A/T Site - Shanghai, China)	CAT (Diodes Internal A/T Site - Chengdu, China)
	No Bar "-" on Date Code for SAT	Date code format change from YM to YW ; No bar on Date Code	Date code format change from YM to YW ; Bar "-" above Y (Year) of Date Code
	Marking Format Example: 	Marking Format Example: 	Marking Format Example: 

	CURRENT	NEW		
SOT23	NAT (Diodes Internal A/T Site - Neuhaus, Germany)	SAT (Diodes Internal A/T Site - Shanghai, China)	CAT (Diodes Internal A/T Site - Chengdu, China)	NAT (Diodes Internal A/T Site - Neuhaus, Germany)
	No Bar "-" and No Date Code	Addition of Date Code ; No bar on Date Code	Addition of Date Code ; Bar "-" above Y (Year) of Date Code	Addition of Date Code ; Bar "-" above W (Week) of Date Code
	Marking Format Example: 	Marking Format Example: 	Marking Format Example: 	Marking Format Example: 
	SAT (Diodes Internal A/T Site - Shanghai, China)	SAT (Diodes Internal A/T Site - Shanghai, China)	CAT (Diodes Internal A/T Site - Chengdu, China)	
	No Bar "-" and YM Date code format	Date code format change from YM to YW ; No bar on Date Code	Date code format change from YM to YW ; Bar "-" above Y (Year) of Date Code	
	Marking Format Example: 	Marking Format Example: 	Marking Format Example: